

FIG. 1

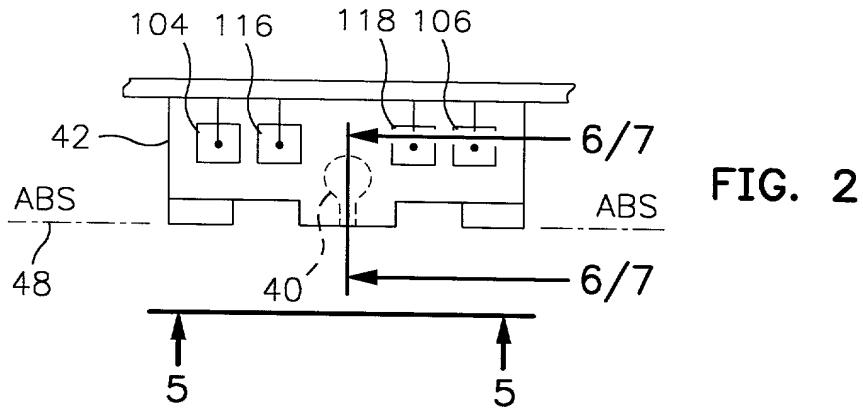


FIG. 2

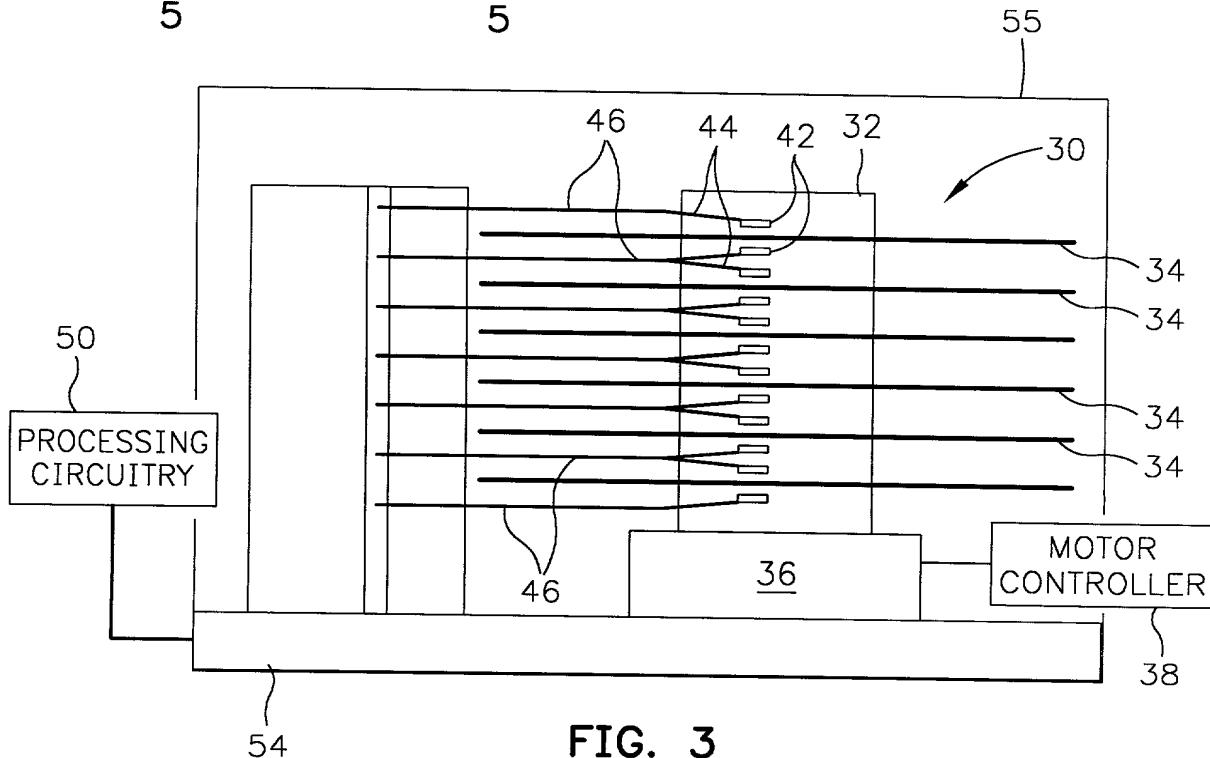


FIG. 3

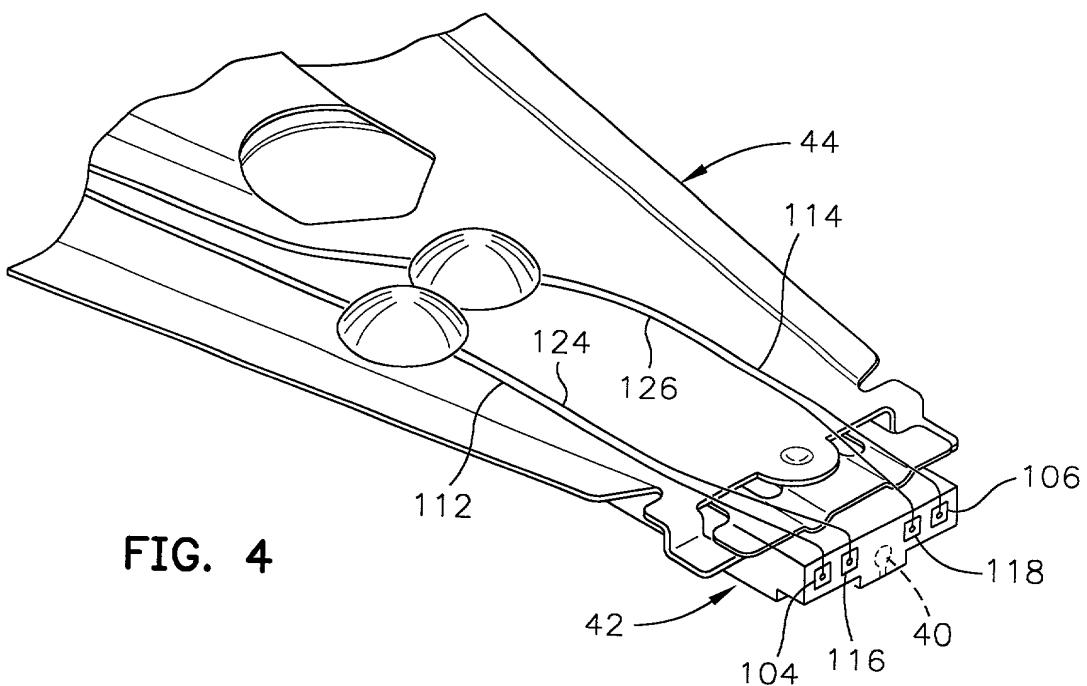


FIG. 4

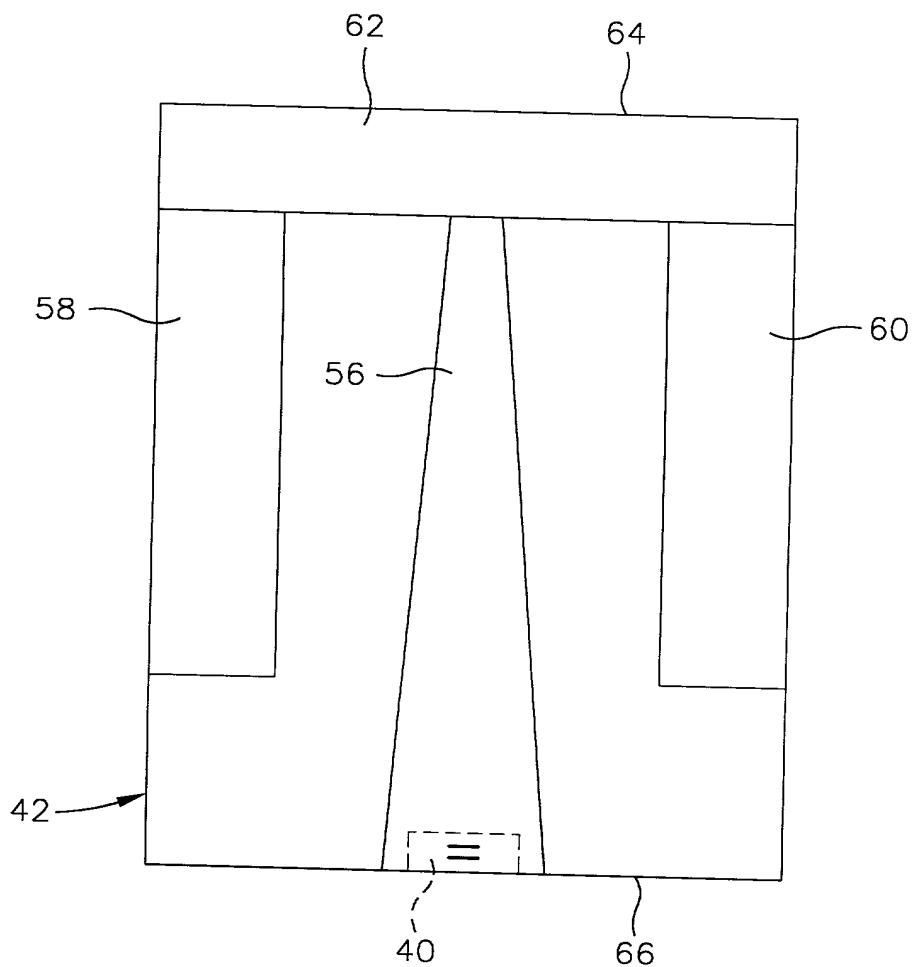


FIG. 5

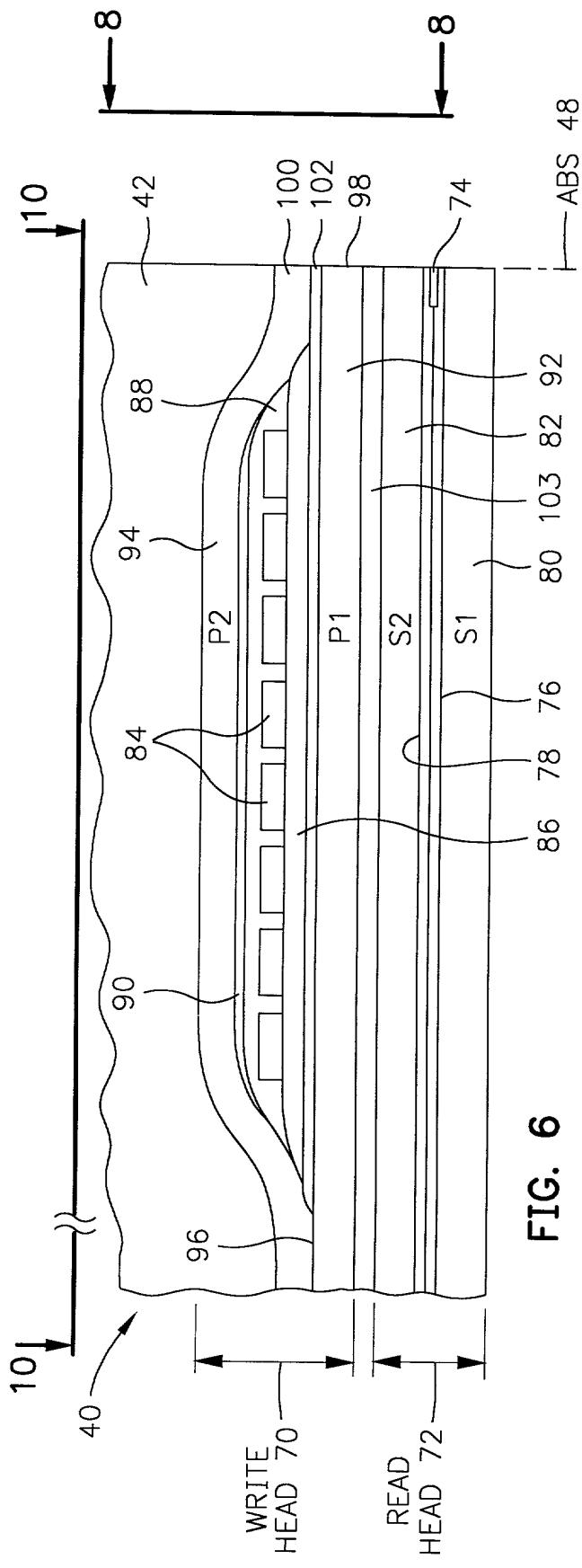


FIG. 6

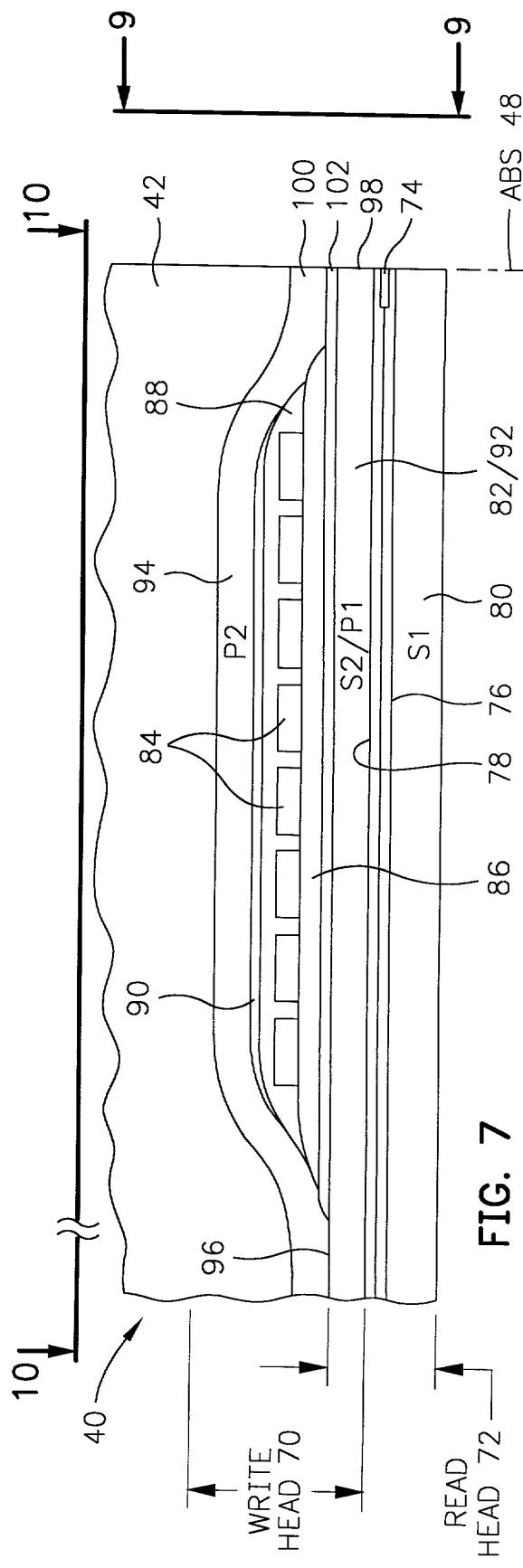
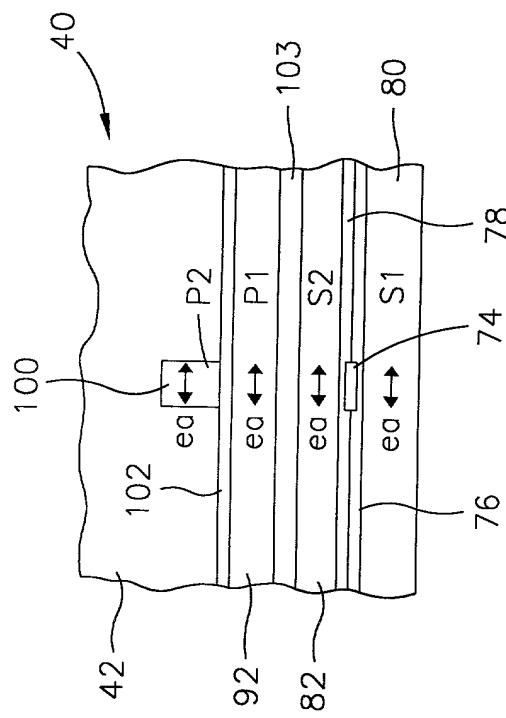
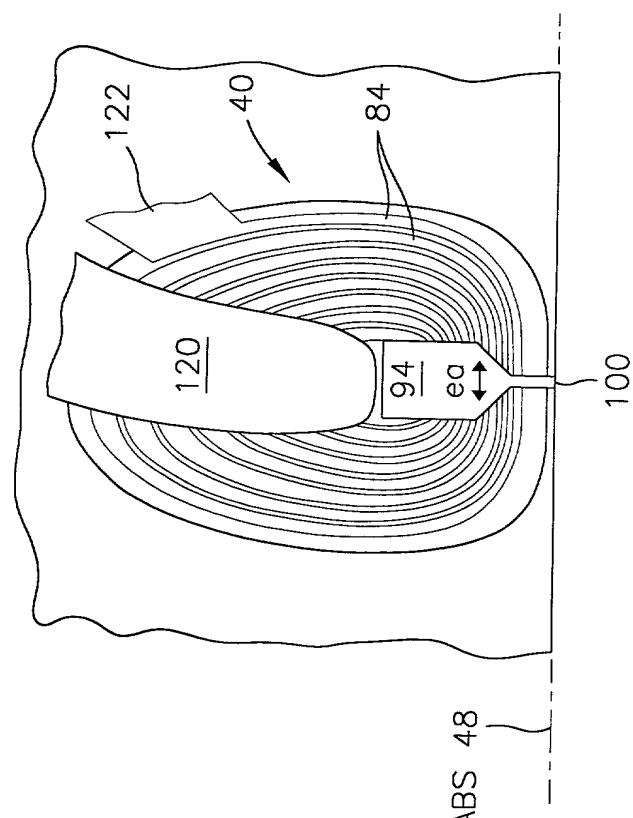


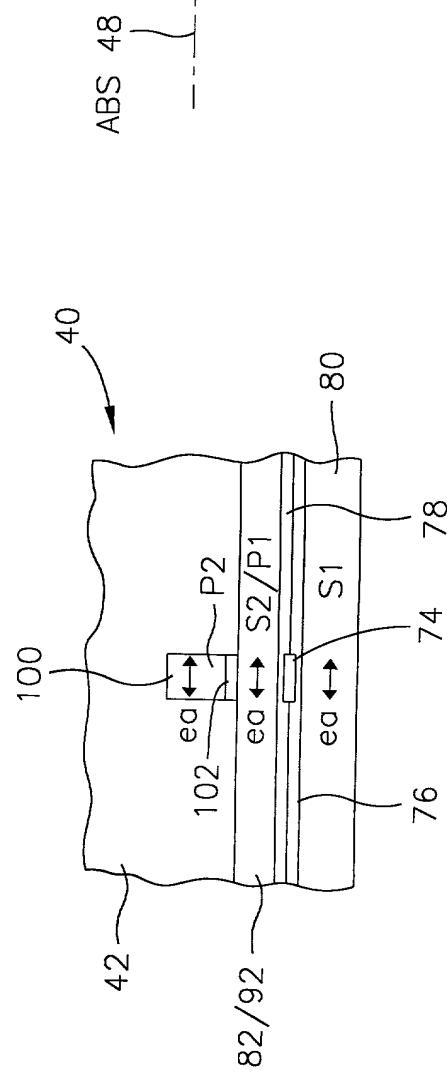
FIG. 7



**FIG. 8**



**FIG. 10**



**FIG. 9**

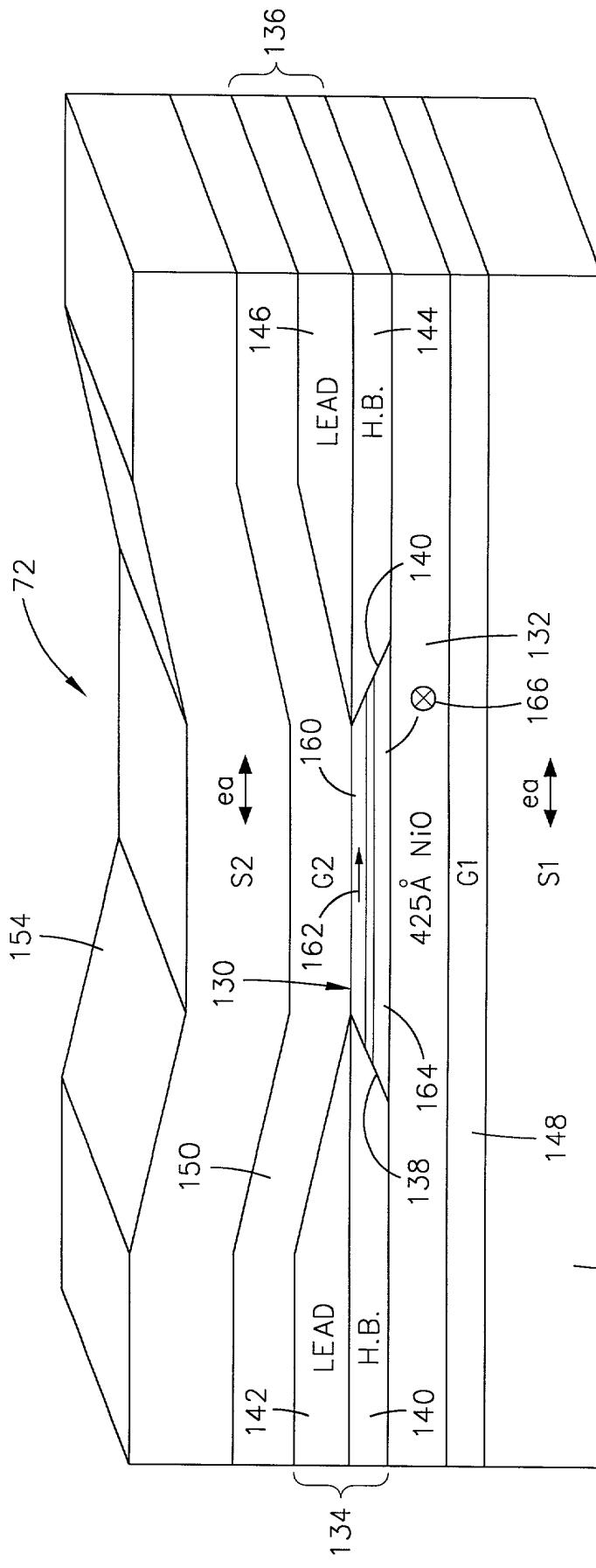
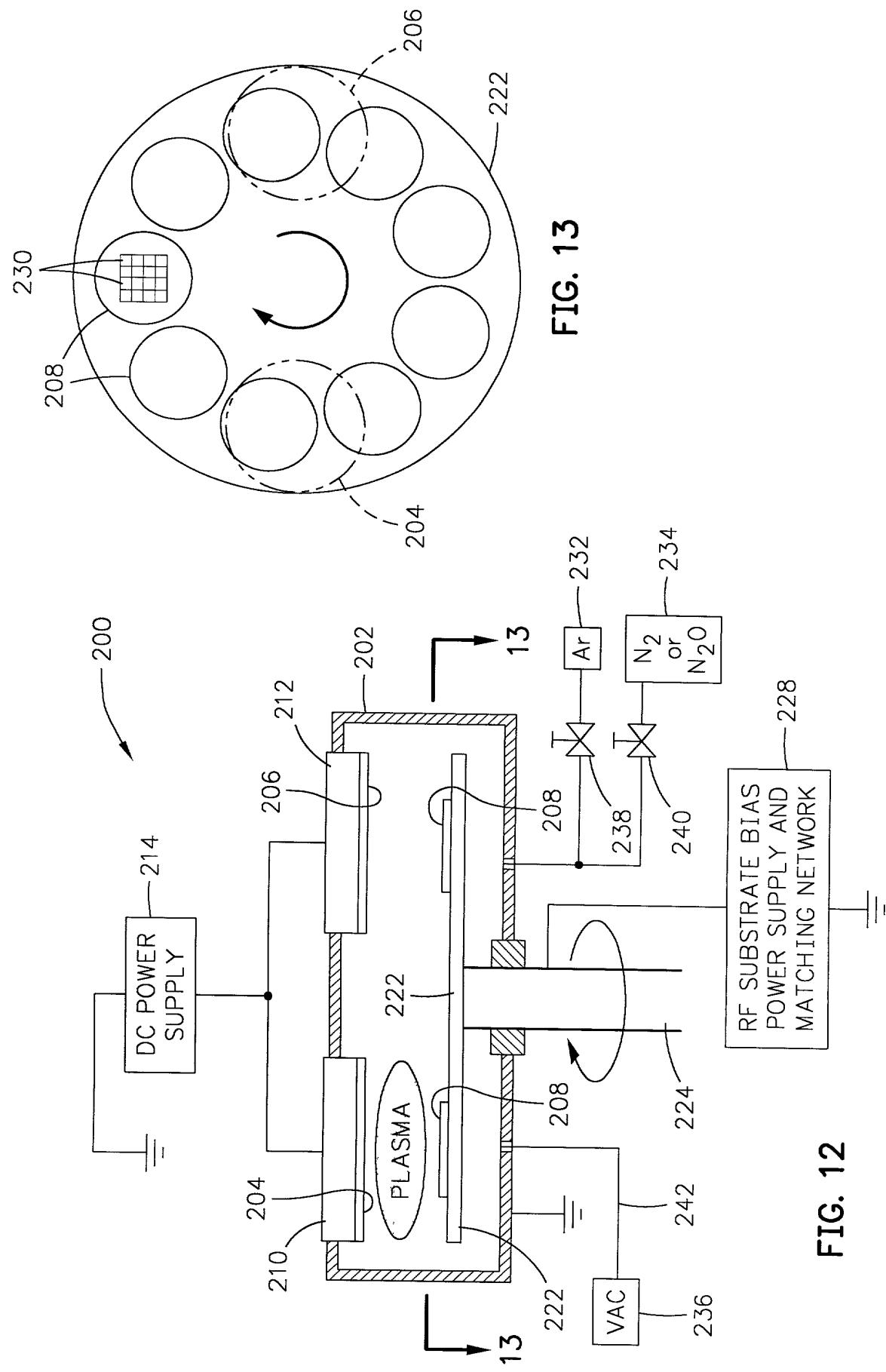


FIG. 11  
(ABS)



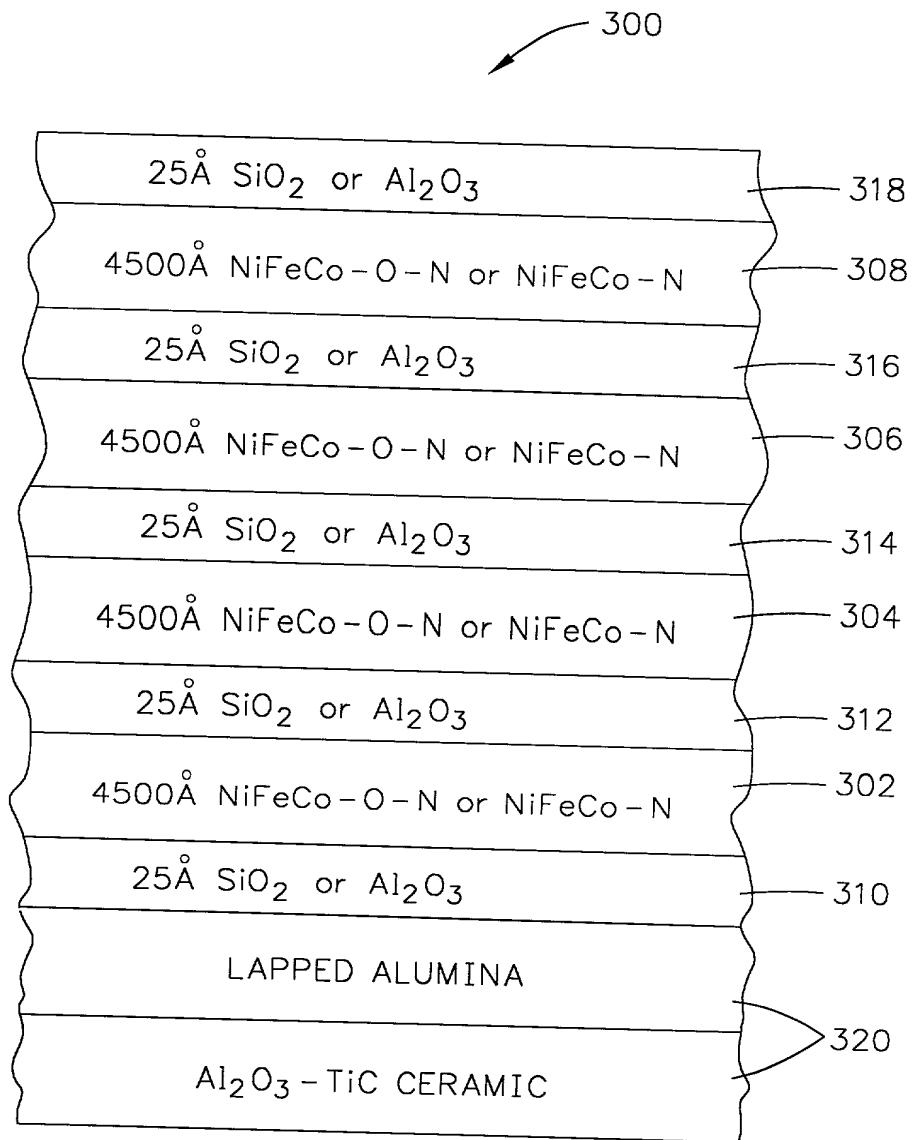
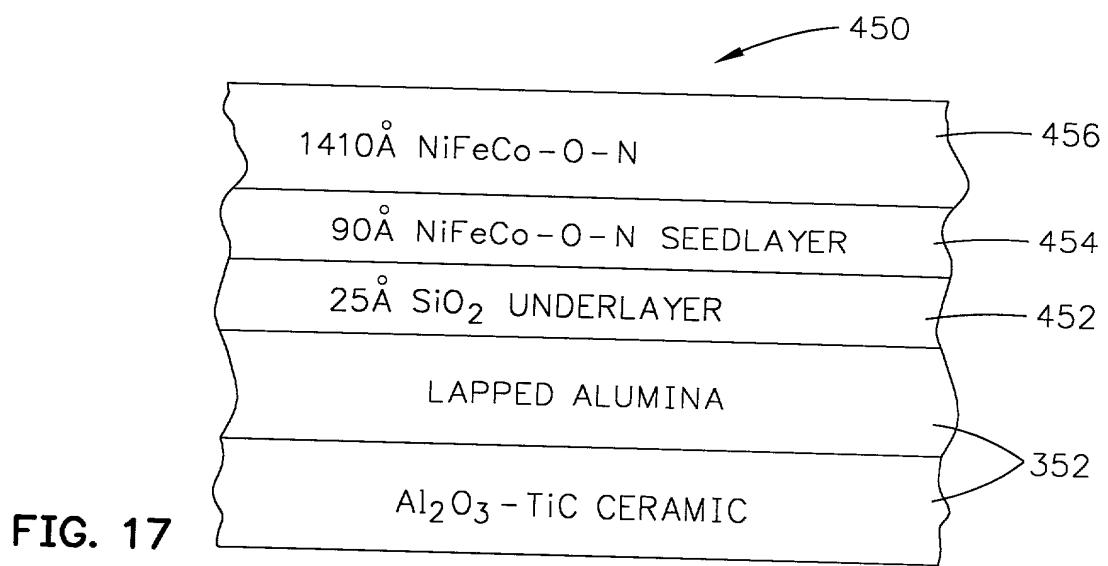
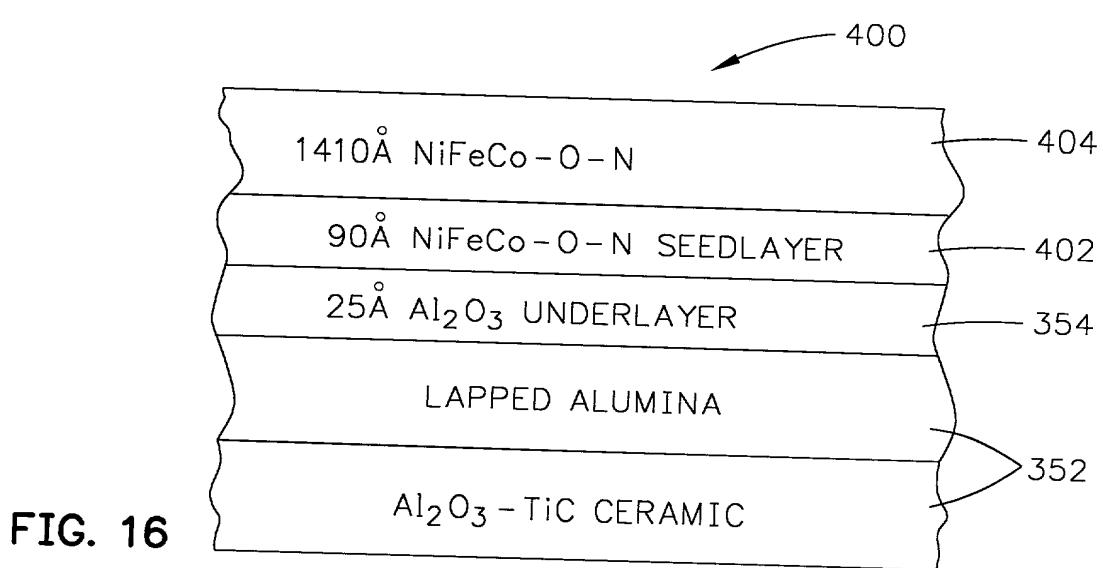
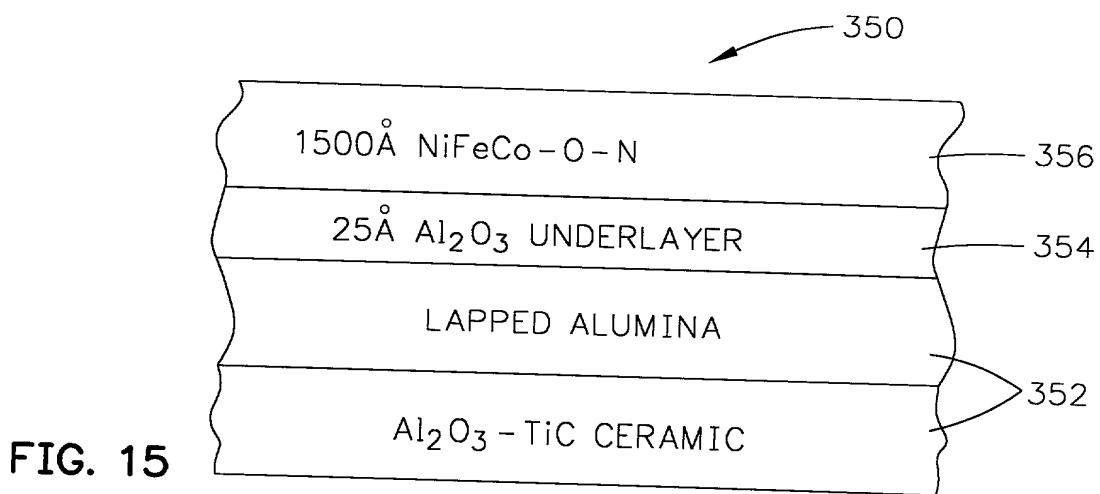
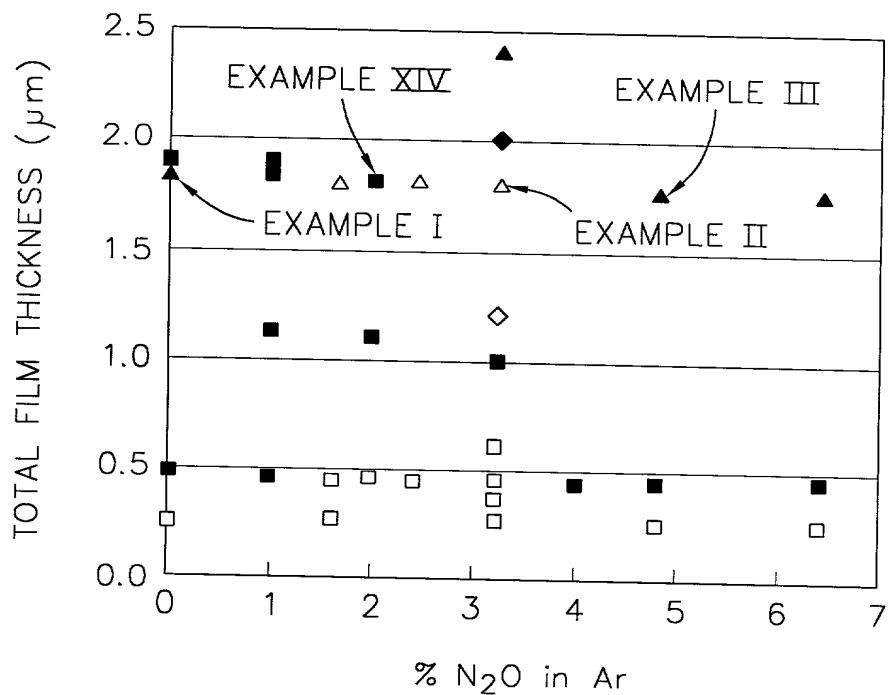


FIG. 14



THICKNESS AND  $N_2O$  CONCENTRATION  
DEPENDENCE OF IN-PLANE AND VERTICAL  $H_k$  IN  
SINGLE LAYER AND LAMINATED NiFeCo-O-N FILMS  
(DC MAG 1750 W,  $2.0 \times 10^{-3}$  mbar, NO BIAS)



- SINGLE LAYER FILMS - IN PLANE  $H_k$
- ◇ 2X LAMINATED FILMS - IN PLANE  $H_k$
- △ 4X LAMINATED FILMS - IN PLANE  $H_k$
- SINGLE LAYER FILMS - VERTICAL  $H_k$
- ◆ 2X LAMINATED FILMS - VERTICAL  $H_k$
- ▲ 4X LAMINATED FILMS - VERTICAL  $H_k$

FIG. 18

THICKNESS AND  $N_2$  CONCENTRATION  
DEPENDENCE OF IN-PLANE AND VERTICAL  $H_k$  IN  
SINGLE LAYER AND LAMINATED NiFeCo-N FILMS  
(DC MAG 1750 W,  $2.0 \times 10^{-3}$  mbar, NO BIAS)

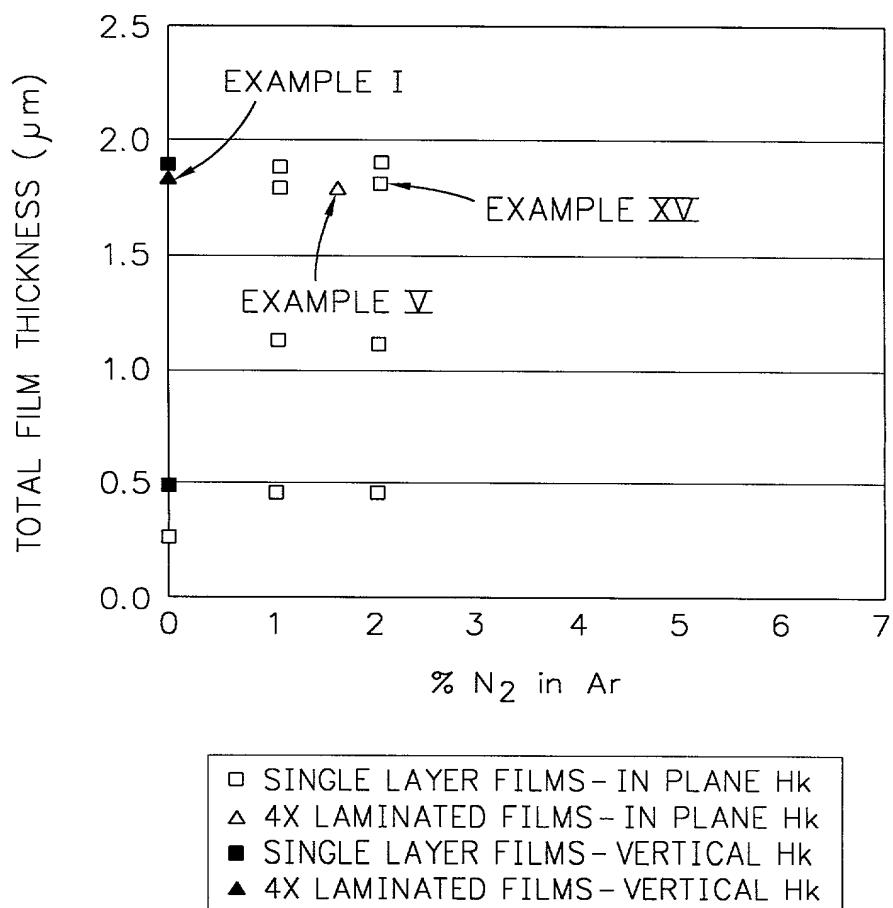
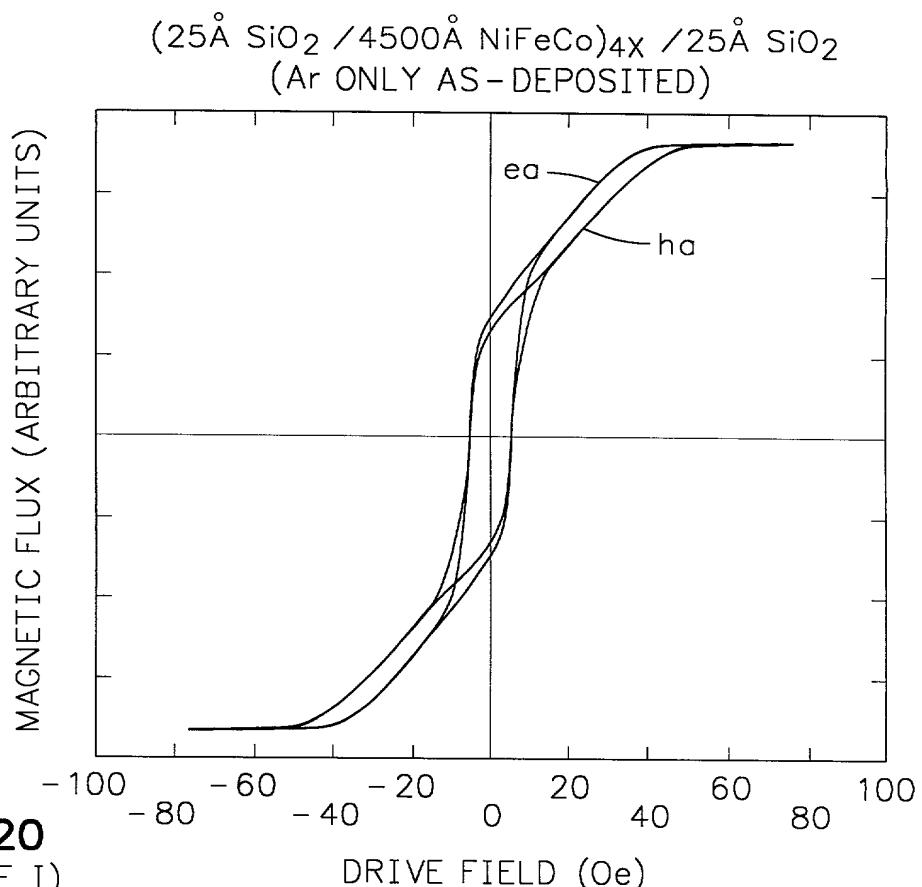
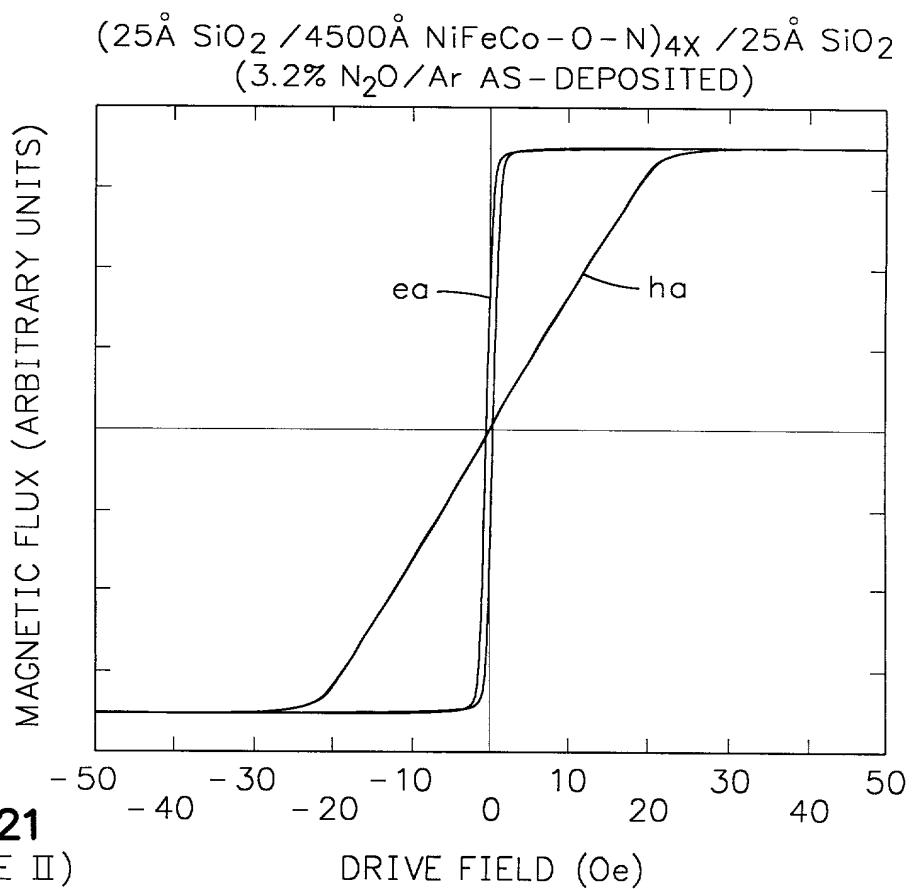


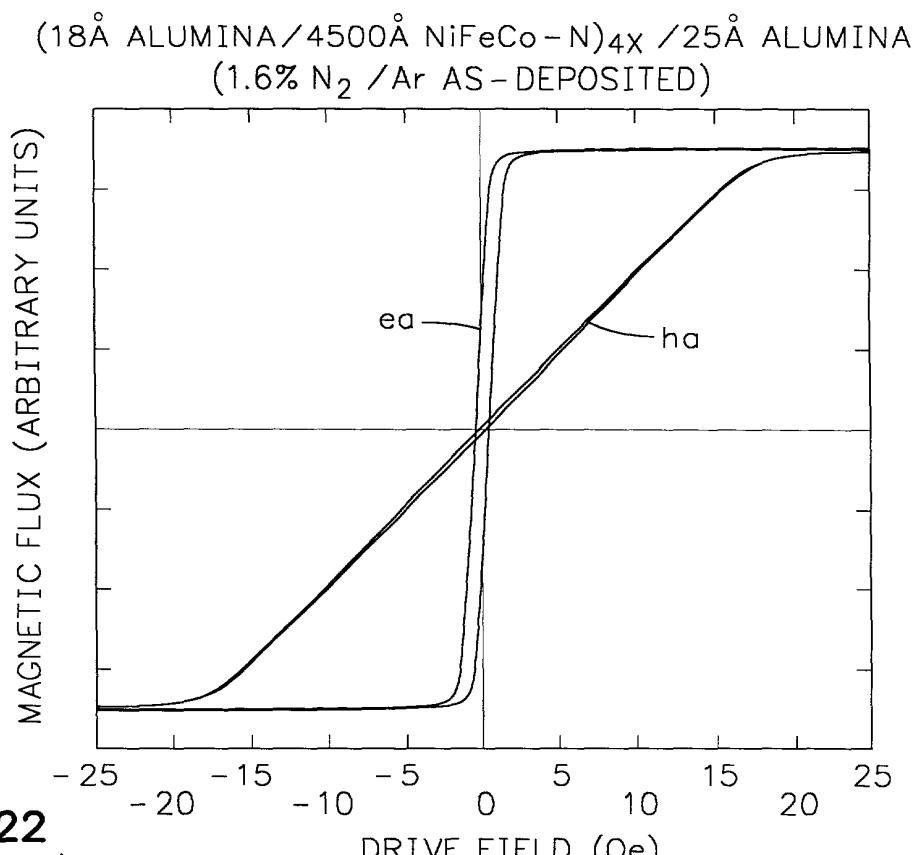
FIG. 19



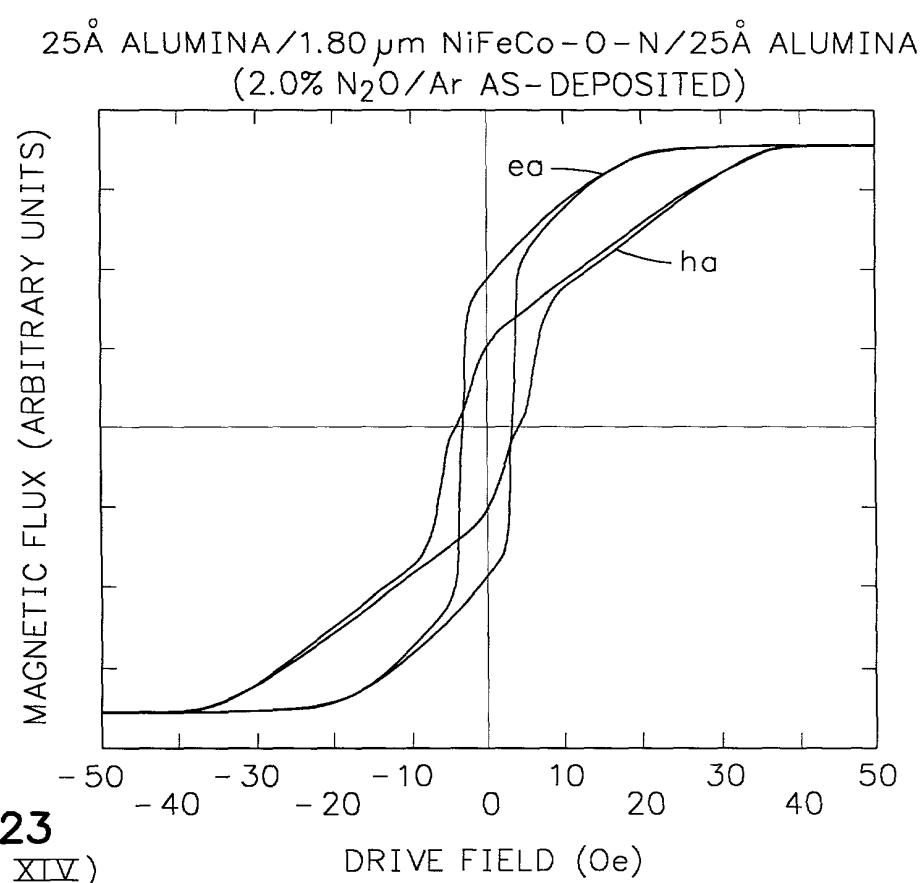
**FIG. 20**  
(EXAMPLE I)



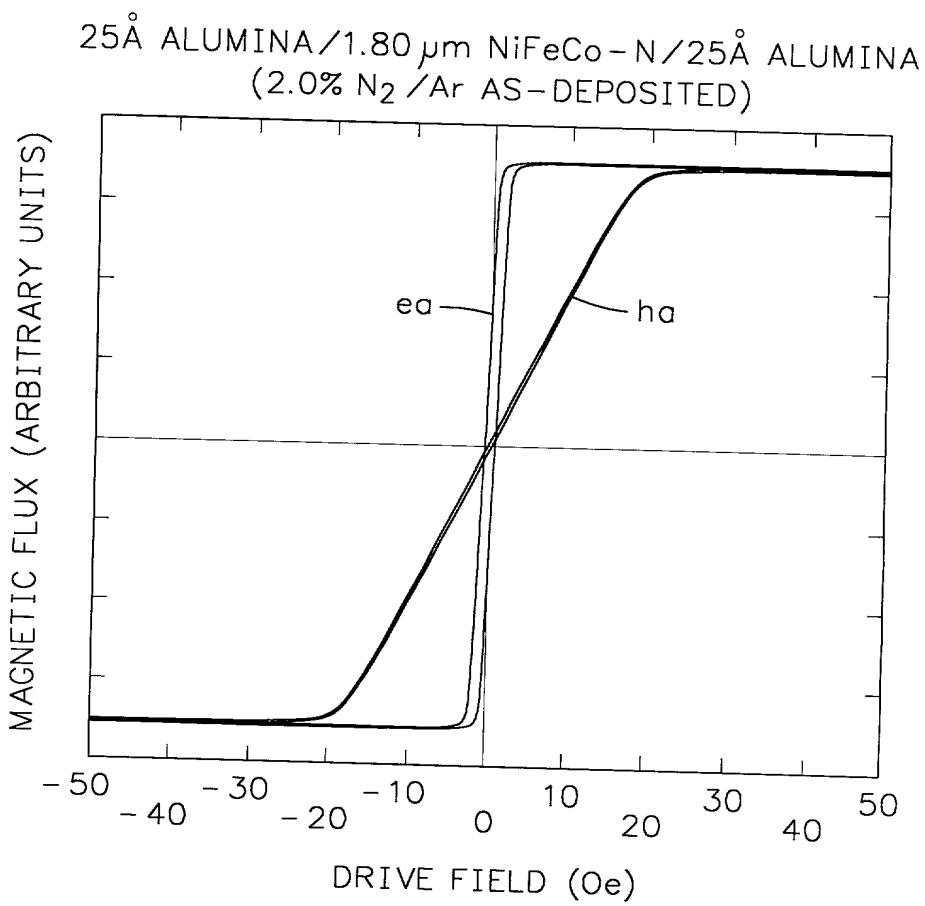
**FIG. 21**  
(EXAMPLE II)



**FIG. 22**  
(EXAMPLE IV)



**FIG. 23**  
(EXAMPLE XIV)



**FIG. 24**  
(EXAMPLE XXV)

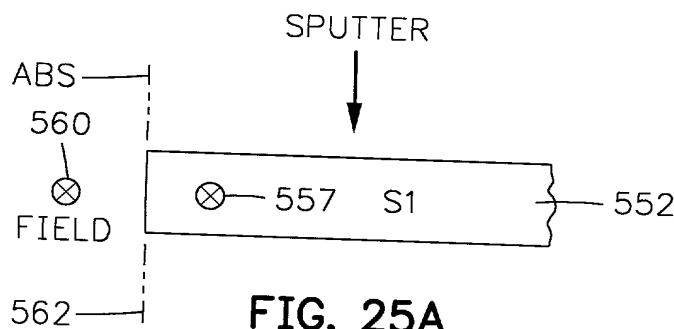


FIG. 25A

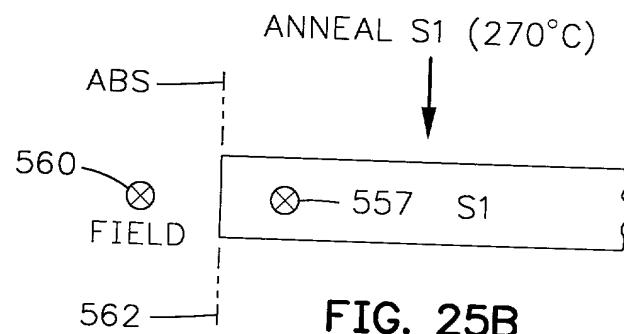


FIG. 25B

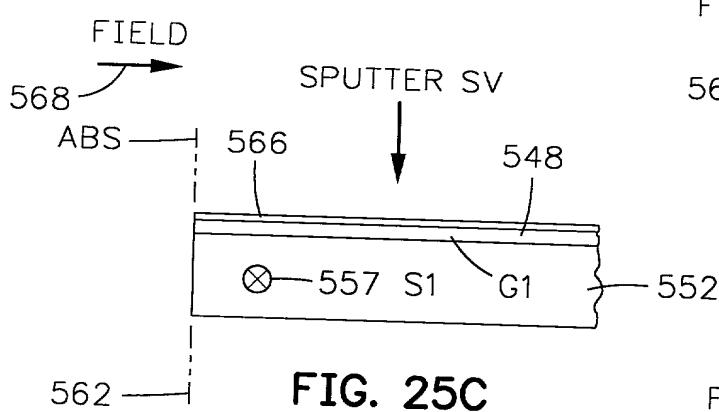


FIG. 25C

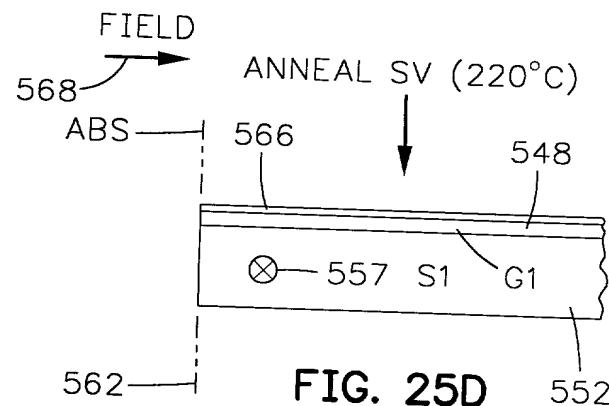


FIG. 25D

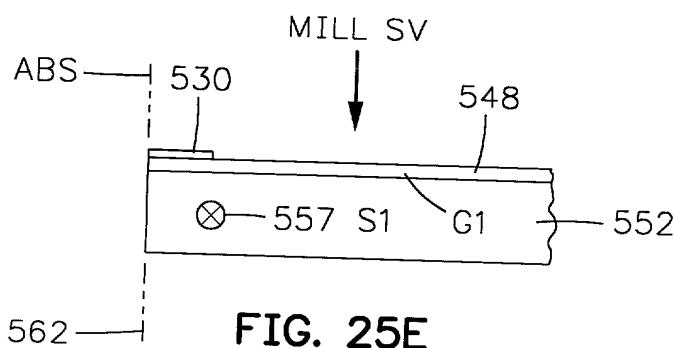


FIG. 25E

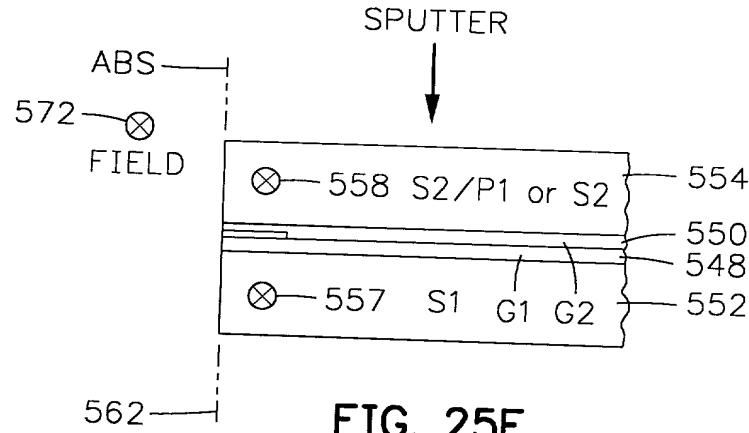


FIG. 25F

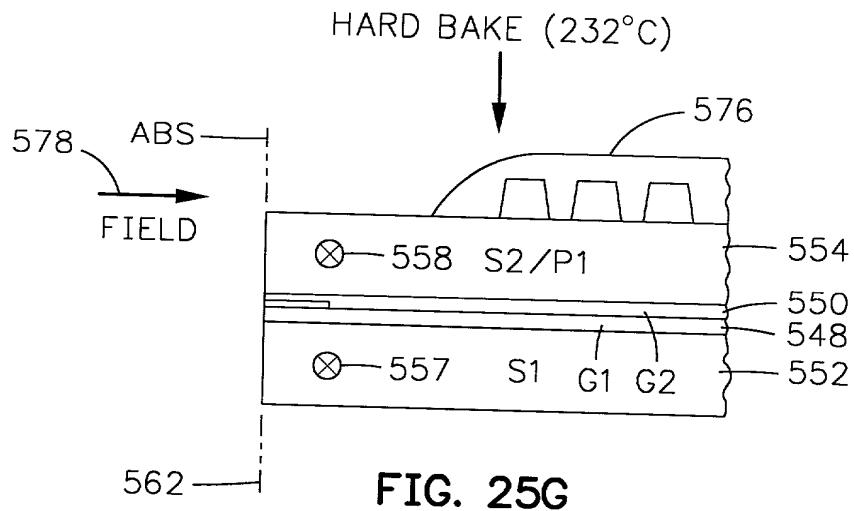


FIG. 25G

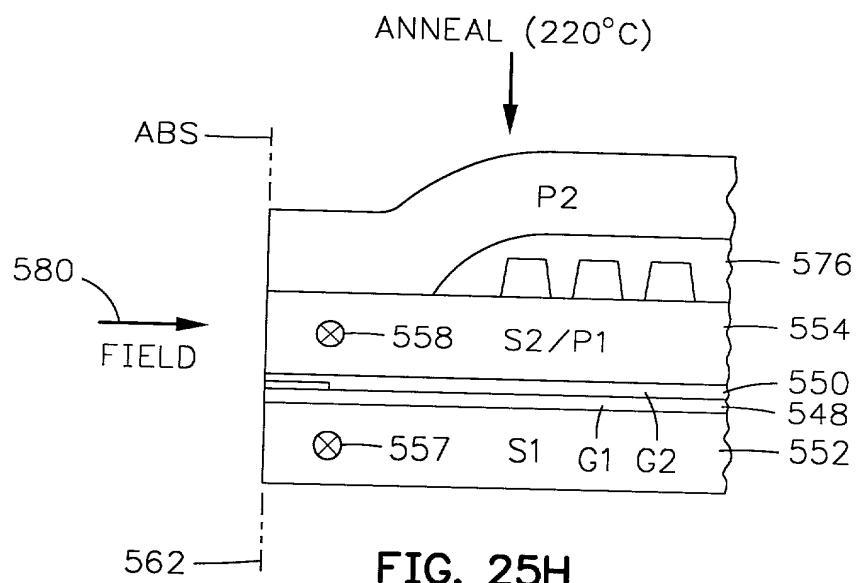


FIG. 25H

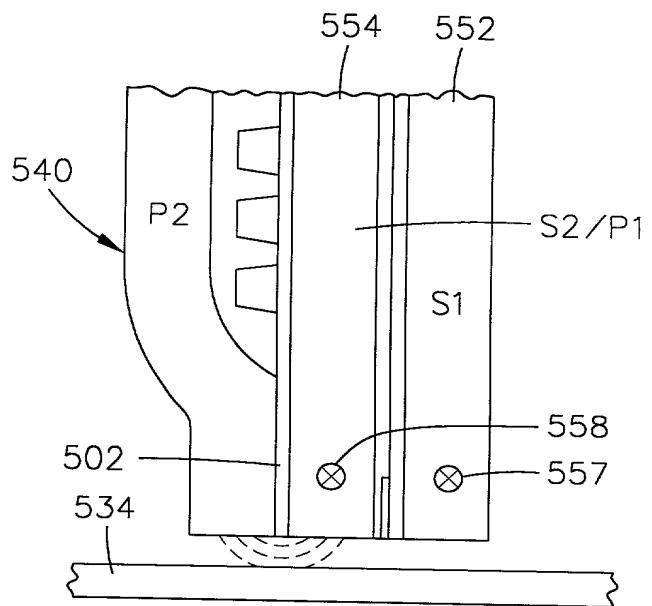


FIG. 26

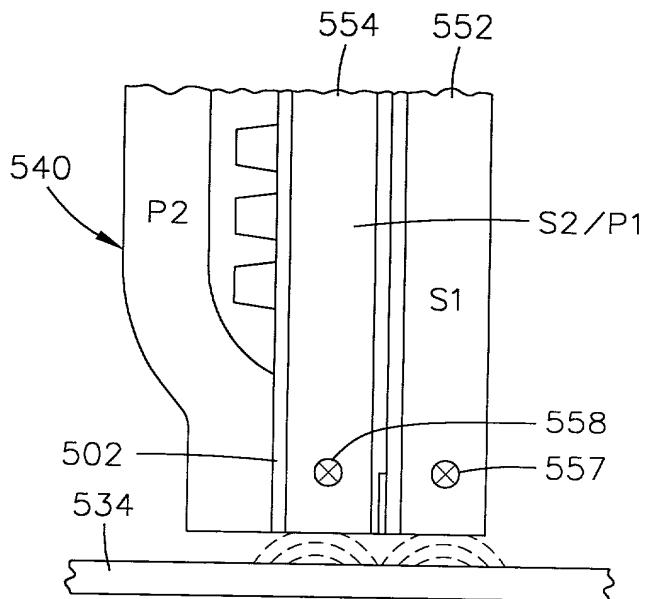
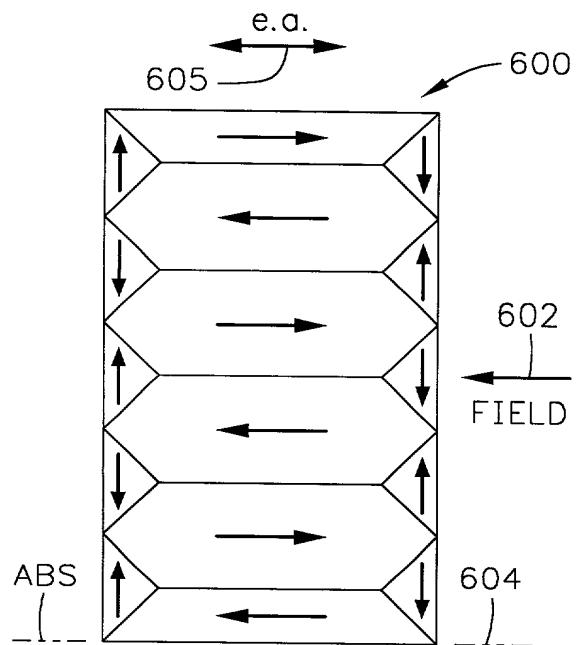
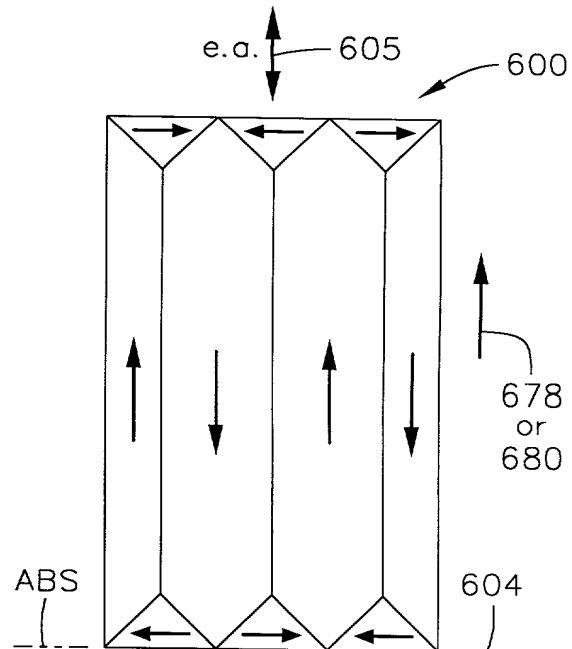


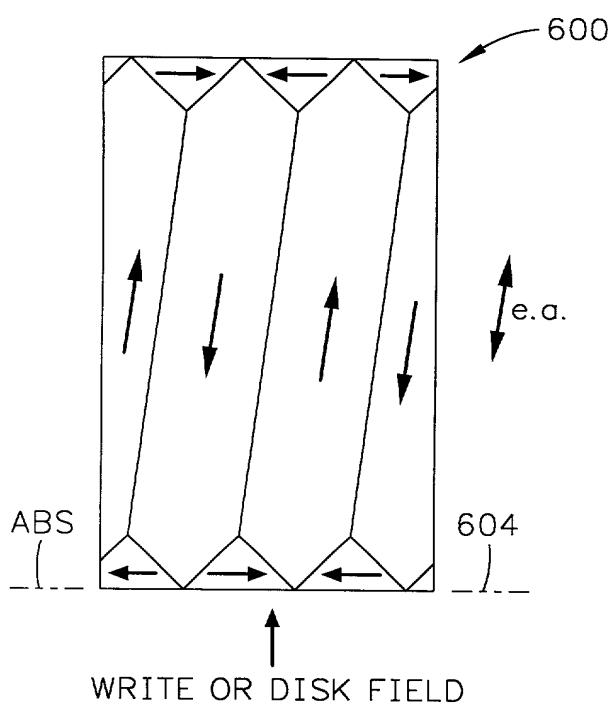
FIG. 27



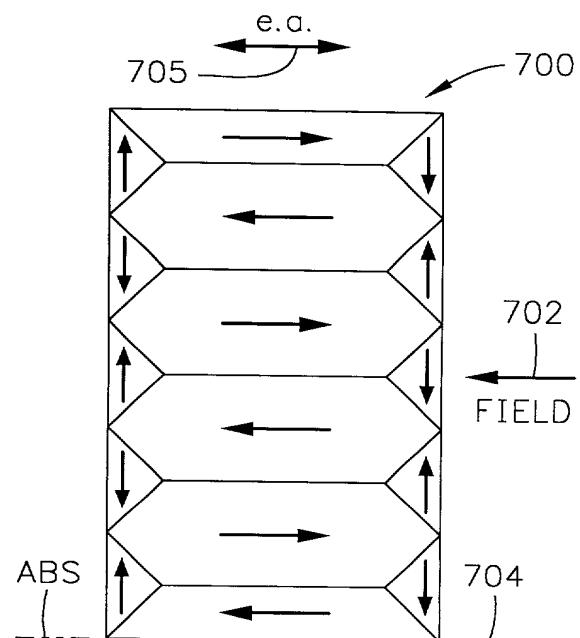
**FIG. 28A**  
(PRIOR ART)



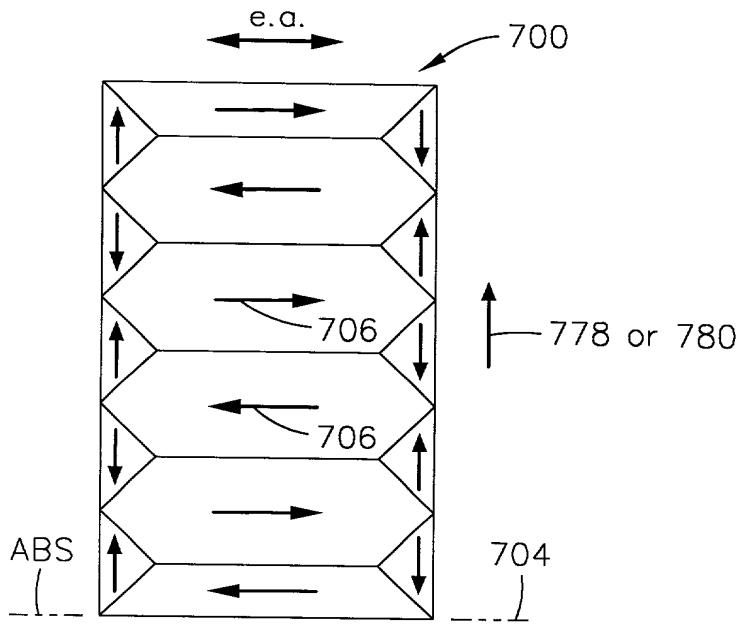
**FIG. 28B**  
(PRIOR ART)



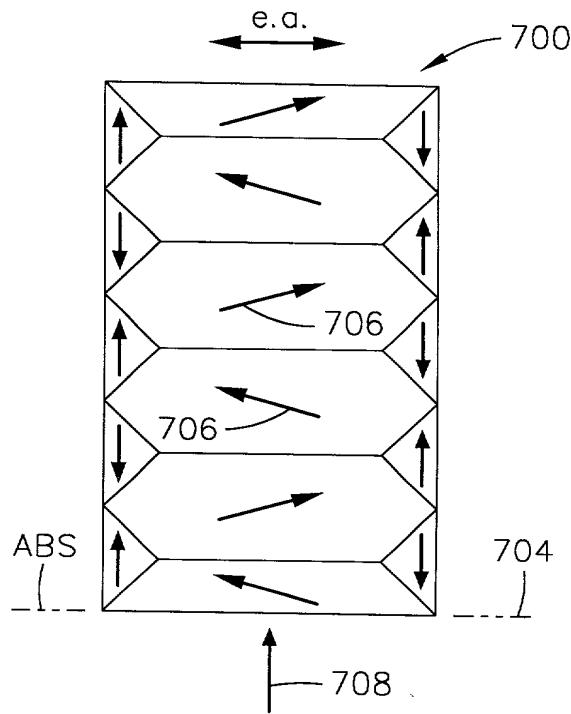
**FIG. 28C**  
(PRIOR ART)



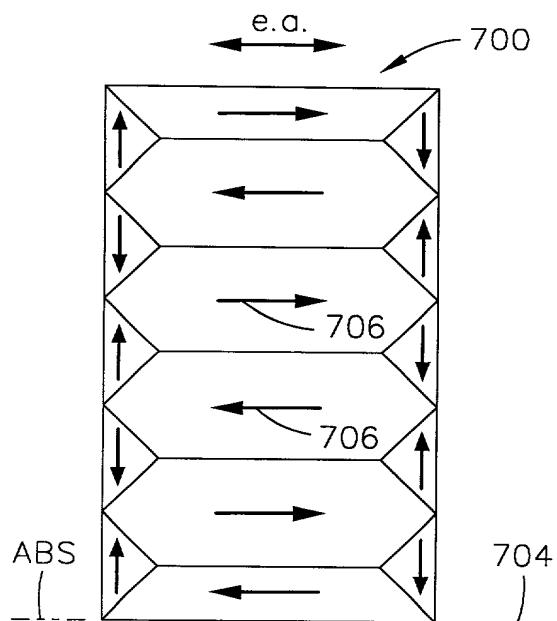
**FIG. 29A**



**FIG. 29B**  
 NiFeCo[-O]-N AFTER HARDBAKE  
 ANNEALING OR RESETTING  
 IN THE PRESENCE OF A FIELD  
 PERPENDICULAR TO THE ABS



**FIG. 29C**



**FIG. 29D**